SVX3D 4-in run yields

1st Honeywell batch (15 wafers, 14 probed):
Good dies: 50.1%
Good + Fair dies: 59.6%

2nd Honeywell batch (100 wafers, 100 probed):
Good dies: 50.6%
Good + Fair dies: 62.5%

All 4-in combined:
Dies probed: 5906 (100%)
Good dies: 2987 (50.6%)
Good + Fair dies: 3672 (62.2%)

The quality maps are on the WWW at
http://cdfsg6.lbl.gov/~igv/svxmaps.html